

# SANYO Semiconductors DATA SHEET

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# LC717A10AJ

# Capacitance-Digital-Converter LSI for Electrostatic Capacitive Touch Sensors

#### Overview

The LC717A10AJ is a high-performance and low-cost capacitance-digital-converter LSI for electrostatic capacitive touch sensor, especially focused on usability.

It has 16 channels capacitance-sensor input. This makes it ideal for use in the products that need many switches. Since the calibration function and the judgment of ON/OFF are automatically performed in LSI internal, it can make development time more short. A detection result (ON/OFF) for each input can be read out by the serial interface (I<sup>2</sup>C compatible bus or SPI).

Also, measurement value of each input can be read out as 8-bit digital data. Moreover, gain and other parameters can be adjusted using serial interface.

#### **Features**

- Detection system: Differential capacitance detection (Mutual capacitance type)
- Input capacitance resolution: Can detect capacitance changes in the femto Farad order
- Measurement interval (16 differential inputs): 30ms (Typ) (at initial configuration),

6ms (Typ) (at minimum interval configuration)

- External components for measurement: Not required
- Interface: I<sup>2</sup>C \* compatible bus or SPI selectable.
- Current consumption:  $570\mu A$  (Typ) (V<sub>DD</sub> = 2.8V), 1.3mA (Typ) (V<sub>DD</sub> = 5.5V)
- Supply voltage: 2.6V to 5.5VDetection operations: Switch
- Packages: SSOP30
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# **Specifications**

**Absolute Maximum Ratings** at Ta = +25°C

Parameter	Symbol	Ratings (V <sub>SS</sub> = 0V)	Unit	Remarks
Supply voltage	$V_{DD}$	-0.3 to +6.5	٧	
Input voltage	V <sub>IN</sub>	-0.3 to V <sub>DD</sub> +0.3	٧	*1
Output voltage	V <sub>OUT</sub>	-0.3 to V <sub>DD</sub> +0.3	٧	*2
Power dissipation	Pd max	160	mW	Ta = +105°C, Mounted on a substrate *3
Storage temperature	Tstg	-55 to +125	°C	

- \*1) Apply to Cin0 to 15, Cref, CrefAdd, nRST, SCL, SDA, SA0, SA1, SCK, SI, nCS
- \*2) Apply to Cdrv, SDA, SO, INTOUT
- \*3) Single-layer glass epoxy board (76.1×114.3×1.6t mm)

**Recommended Operating Conditions** 

Parameter	Symbol	Conditions	min	typ	max	Unit	Remarks
Operating supply voltage	$V_{DD}$		2.6		5.5	٧	
Supply ripple + noise	Vpp				±20	mV	*1
Operating temperature	Topr		-40	25	105	°C	

<sup>\*1)</sup> We recommend connecting large and small capacitance between V<sub>DD</sub> and V<sub>SS</sub>. In this case, the small capacitance is equal to or more than 0.1µF, and layout nearby LSI.

# **Electrical Characteristics** at $V_{SS}$ = 0V, $V_{DD}$ = 2.6 to 5.5V, Ta = -40 to +105°C

- \* Unless otherwise specified, the Cdrv drive frequency is  $f_{CDRV} = 143 \text{kHz}$ .
- \* Not tested at low temperature before shipment.

Parameter	Symbol	Conditions	min	typ	max	Unit	Remarks
Capacitance detection resolution	N				8	bit	
Output noise RMS	N <sub>RMS</sub>	minimum gain setting			±1.0	LSB	*1 *3
Input offset capacitance adjustment range	CoffRANGE			±8.0		pF	*1 *3
Input offset capacitance adjustment resolution	CoffRESO			8		bit	
Cin offset drift	CinDRIFT	minimum gain setting			±8	LSB	*1
Cin detection sensitivity	CinSENSE	minimum gain setting	0.04		0.12	LSB/fF	*2
Cin pin leak current	l <sub>Cin</sub>	Cin = Hi-Z		±25	±500	nA	
Cin allowable parasitic input capacitance	Cin <sub>SUB</sub>	Cin against V <sub>SS</sub>			30	pF	*1 *3
Cdrv drive frequency	fCDRV		100	143	186	kHz	
Cdrv pin leak current	ICDRV	Cdrv = Hi-Z		±25	±500	nA	
nRST minimum pulse width	<sup>t</sup> NRST		1			μs	*1
Power-on reset time	<sup>t</sup> POR				20	ms	*1
Power-on reset operation condition: Hold time	<sup>t</sup> POROP		10			ms	*1
Power-on reset operation condition: Input voltage	V <sub>POROP</sub>				0.1	٧	*1
Power-on reset operation condition: Power supply rise rate	t <sub>VDD</sub>	0V to V <sub>DD</sub>	1			V/ms	*1

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Parameter	Symbol	Conditions	min	typ	max	Unit	Remarks
Pin input voltage	V <sub>IH</sub>	High input	0.8V <sub>DD</sub>			.,	****
	V <sub>IL</sub>	Low input			0.2V <sub>DD</sub>	V	*1 *4
Pin output voltage	VOH	High output (I <sub>OH</sub> = +3mA)	0.8V <sub>DD</sub>			V	*5
	V <sub>OL</sub>	Low output (I <sub>OL</sub> = -3mA)			0.2V <sub>DD</sub>	V	"5
SDA pin output voltage	V <sub>OL</sub> I <sup>2</sup> C	SDA Low output (I <sub>OL</sub> = -3mA)			0.4	٧	
Pin leak current	ILEAK				±1	μΑ	*6
Current consumption	I <sub>DD</sub>	When initial setting and non-touch VDD = 2.8V		570	700	μА	*1 *3
		When initial setting and non-touch $V_{\mathrm{DD}} = 5.5 \mathrm{V}$		1.3	1.6	mA	*1 *3
	I <sub>STBY</sub>	During Sleep process			1	μΑ	*3

<sup>\*1)</sup> Design guarantee values (not tested before shipment)

<sup>\*2)</sup> Measurements conducted using the test mode in the LSI

<sup>\*3)</sup>  $Ta = +25^{\circ}C$ 

<sup>\*4)</sup> Apply to nRST, SCL, SDA, SA0, SA1, SCK, SI, nCS

<sup>\*5)</sup> Apply to Cdrv, SO, INTOUT

<sup>\*6)</sup> Apply to nRST, SCL, SDA, SA0, SA1, SCK, SI, nCS

# **I**<sup>2</sup>C Compatible Bus Timing Characteristics at $V_{SS} = 0$ , $V_{DD} = 2.6$ to 5.5V, $T_a = -40$ to +105°C

\*Not tested at low temperature before shipment

Parameter	Symbol	Pin Name	Conditions	min	typ	max	Unit	Remarks
SCL clock frequency	fSCL	SCL				400	kHz	
START condition hold time	tHD;STA	SCL		0.0				
	,	SDA		0.6			μs	
SCL clock low period	tLOW	SCL		1.3			μs	
SCL clock high period	tHIGH	SCL		0.6			μs	
Repeated START condition	tSU;STA	SCL		0.6				*1
setup time		SDA		0.6			μs	Į
Data hold time	tHD;DAT	SCL		0		0.9		
		SDA		U		0.9	μs	
Data setup time	tSU;DAT	SCL		400				*1
		SDA		100			μs	Į
SDA, SCL rise/fall time	t <sub>r</sub> / t <sub>f</sub>	SCL				000		*1
		SDA				300	μs	- 1
STOP condition setup time	tsu:sto	SCL		0.0				
	, ,	SDA		0.6			μs	
STOP-to-START bus release	tBUF	SCL		1.3				*1
time		SDA		1.3			μs	- 1

<sup>\*1)</sup> Design guarantee values (not tested before shipment)

# SPI Bus Timing Characteristics at $V_{SS}$ = 0, $V_{DD}$ = 2.6 to 5.5V, Ta = -40 to +105°C

\*Not tested at low temperature before shipment

Parameter	Symbol	Pin Name	Conditions	min	typ	max	Unit	Remarks	
SCK clock frequency	fSCK	SCK				5	MHz		
SCK clock Low time	t <sub>LOW</sub>	SCK		90			ns	*1	
SCK clock High time	tHIGH	SCK		90			ns	*1	
Input signal rise/fall time	t <sub>r</sub> / t <sub>f</sub>	nCS							
		SCK				300	ns	*1	
		SI							
nCS setup time	tsu;NCS	nCS		90			ns	*1	
		SCK		90			115	'	
SCK clock setup time	tsu;sck	nCS		90			ns	*1	
		SCK		90			115	I	
Data setup time	tsu;si	SCK		20			ns	*1	
		SI		20			115	'	
Data hold time	tata hold time thD;SI SCK 30			ns	*1				
		SI		30			115	'	
nCS hold time	tHD;NCS	nCS		90			ns	*1	
		SCK		30			113	'	
SCK clock hold time	tHD;SCK	nCS		90			ns	*1	
		SCK		30			113	'	
nCS standby pulse width	<sup>t</sup> CPH	nCS		90			ns	*1	
Output high impedance time	<sup>t</sup> CHZ	nCS				00		*1	
from nCS		SO				80	ns	- 1	
Output data determination time	t <sub>V</sub>	SCK				00		*1	
		SO				80	ns	- 1	
Output data hold time	tHD;SO	SCK		0				*1	
		SO		0			ns		
Output low impedance time	t <sub>CLZ</sub>	SCK		0			20	*1	
from SCK clock		SO		"			ns	'	

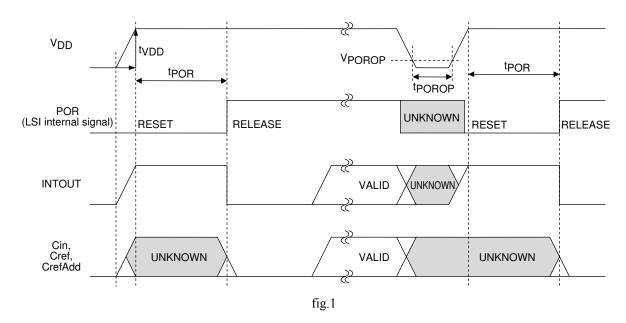
<sup>\*1)</sup> Design guarantee values (not tested before shipment)

#### Power-on Reset (POR)

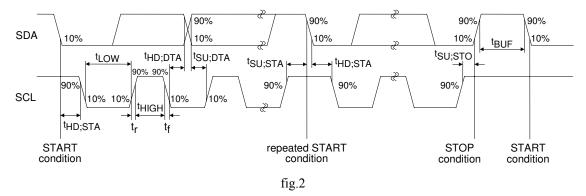
When power is turned on, power-on reset is enabled inside the LSI and its state is released after a certain power-on reset time, tpOR. Power-on Reset operation condition; Power supply rise rate tVDD must be at least 1V/ms.

Since INTOUT pin changes from "High" to "Low" at the same time as the released of power-on reset, it is possible to verify the timing of release of power-on reset externally.

During power-on reset, Cin, Cref and CrefAdd are unknown.



# I<sup>2</sup>C Compatible Bus Data Timing



# I<sup>2</sup>C Compatible Bus Communication Formats

• Write format (data can be written into sequentially incremented addresses)

START	Slave Address	Write=L	ACK	Register Address (N)	ACK	Data written to Register Address (N)	ACK	Data written to Register Address (N+1)	ACK	STOP
			Slave		Slave		Slave		Slave	
					fig.3					

• Read format (data can be read from sequentially incremented addresses)

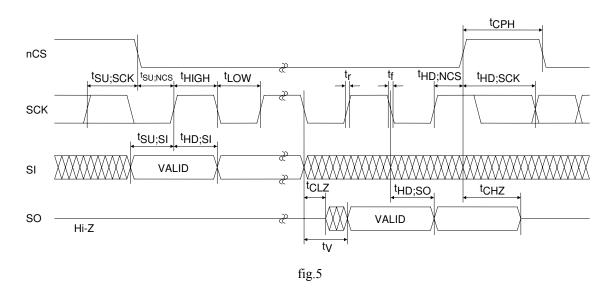
START	Slave Address	Write=L	ACK	Register Address (N)	ACK				
			Slave		Slave				
RESTART	Slave Address	Read=H	ACK	Data read from Register Address (N)	ACK	Data read from Register Address (N+1)	ACK	Data read from Register Address (N+2)	NAC
			Slave		Maste		Maste	r	Maste
				1	fig 4				

# I<sup>2</sup>C Compatible Bus Slave Address

Selection of two kinds of addresses is possible through the SA0 and SA1 terminals.

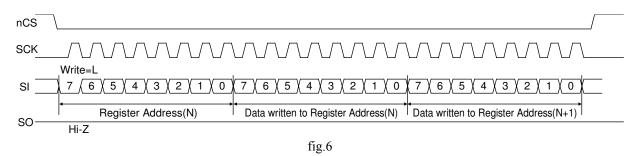
SA1 input	SA0 input	7bit slave address	Binary notation	8bit slave address
Low	Low	0x16	00101100b (Write)	0x2C
			00101101b (Read)	0x2D
Low	High	0x17	00101110b (Write)	0x2E
			00101111b (Read)	0x2F
High	Low	0x18	00110000b (Write)	0x30
			00110001b (Read)	0x31
High	High	0x19	00110010b (Write)	0x32
			00110011b (Read)	0x33

# SPI Data Timing (SPI Mode 0 / Mode 3)

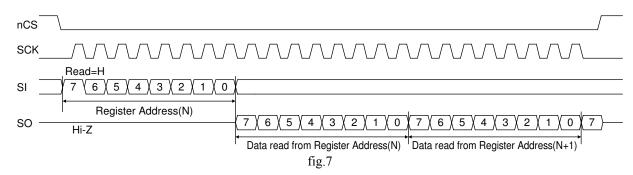


# **SPI Communication Formats** (Example of Mode 0)

• Write format (data can be written into sequentially incremented addresses with preserving nCS = L)



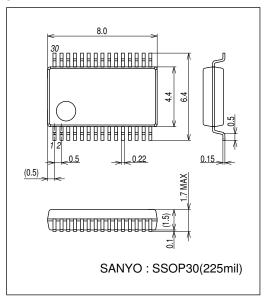
• Read format (data can be read from sequentially incremented addresses with preserving nCS = L)



# Package Dimensions [LC717A10AJ]

unit: mm (typ)

3421

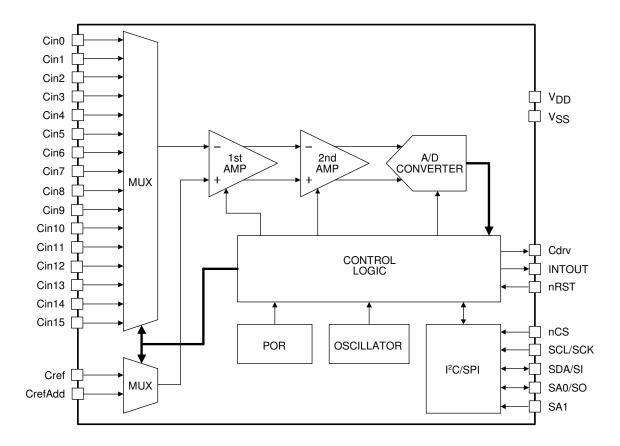


# **Pin Assignment**

Pin No.	Pin Name	Pin No.	Pin Name
1	$v_{DD}$	16	Cref
2	V <sub>SS</sub>	17	CrefAdd
3	Non Connect *1	18	Cdrv
4	Cin4	19	INTOUT
5	Cin5	20	SA1
6	Cin6	21	SCL/SCK
7	Cin7	22	SDA/SI
8	Cin8	23	SA0/SO
9	Cin9	24	nCS
10	Cin10	25	nRST
11	Cin11	26	Non Connect *1
12	Cin12	27	Cin0
13	Cin13	28	Cin1
14	Cin14	29	Cin2
15	Cin15	30	Cin3

<sup>\*1)</sup> connect to GND when mounted

# **Block Diagram**



LC717A10AJ is capacitance-digital-converter LSI capable of detecting changes in capacitance in the order of femto Farads. It consists of an oscillation circuit that generates the system clock, a power-on reset circuit that resets the system when the power is turned on, a multiplexer that selects the input channels, a two-stage amplifier that detects the changes in the capacitance and outputs analog-amplitude values, a A/D converter that converts the analog-amplitude values into digital data, an I<sup>2</sup>C compatible bus or a SPI that enables serial communication with external devices and a control logic that controls the entire chip.

# **Pin Functions**

Pin Name	I/O	Pin Functions	Pin Type
Cin0	I/O	Capacitance sensor input	
Cin1	I/O	Capacitance sensor input	
Cin2	I/O	Capacitance sensor input	
Cin3	I/O	Capacitance sensor input	
Cin4	I/O	Capacitance sensor input	
Cin5	I/O	Capacitance sensor input	V <sub>DD</sub> Å
Cin6	I/O	Capacitance sensor input	
Cin7	I/O	Capacitance sensor input	AMP AMP
Cin8	I/O	Capacitance sensor input	-
Cin9	I/O	Capacitance sensor input	
Cin10	I/O	Capacitance sensor input	
Cin10	I/O		$\dashv$
	<del>                                     </del>	Capacitance sensor input	V <sub>SS</sub> ,
Cin12	I/O	Capacitance sensor input	Buffer
Cin13	I/O	Capacitance sensor input	
Cin14	I/O	Capacitance sensor input	
Cin15	I/O	Capacitance sensor input	
Cref	I/O	Reference capacitance input	
CrefAdd	I/O	Reference capacitance input for addition	
Cdrv	0	Output for capacitance sensors drive	V <sub>DD</sub> Å
INTOUT	0	Interrupt output	Buffer VSS m
SCL/SCK	ı	Clock input (I <sup>2</sup> C) / Clock input (SPI)	V <sub>DD</sub> $\stackrel{\triangle}{\uparrow}$
nCS	ı	Interface selection / Chip select inverting input (SPI)	R R
nRST	I	External reset signal inverting input	
SA1	ı	Slave address selection (I <sup>2</sup> C)	V <sub>SS</sub> ,,,
SDA/SI	1/0	Data input and output (I <sup>2</sup> C) / Data input (SPI)	V <sub>DD</sub> A R R V <sub>SS</sub> W

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Pin Name	I/O	Pin Functions	Pin Type
SA0/SO	I/O	Slave address selection (I <sup>2</sup> C) / Data output (SPI)	V <sub>DD</sub> A R M
$V_{DD}$		Power supply (2.6V to 5.5V) *1	
V <sub>SS</sub>		Ground (Earth) *1 *2	

<sup>\*1)</sup> Inserting a high-valued capacitor and a low-valued capacitor in parallel between V<sub>DD</sub> and V<sub>SS</sub> is recommended. In this case, the small-valued capacitor should be at least 0.1µF, and is mounted near the LSI.

#### **Details of Pin Functions**

#### •Cin0 to Cin15

These are the capacitance-sensor-input pins. These pins are used by connecting them to the touch switch pattern. Cin and the Cdrv wire patterns should be close to each other. By doing so, Cdrv and Cin patterns are capacitively coupled. Therefore, LSI can detect capacitance change near each pattern as 8bit digital data.

However, if the shape of each pattern or the capacitively coupled value of Cdrv is not appropriate, it may not be able to detect the capacitance change correctly.

In this LSI, there is a two-stage amplifier that detects the changes in the capacitance and outputs analog-amplitude values. Cin0 to Cin15 are connected to the inverting input of the 1st amplifier.

During measurement process, channels other than the one being measured are all in "Low" condition. Leave the unused terminals open.

#### •Cref, CrefAdd

These are the reference-capacitance-input pins. These are used by connecting to the wire pattern like Cin pins or are used by connecting any capacitance between this pin and Cdrv pin.

In this LSI, there is a two-stage amplifier that detects the changes in the capacitance and outputs analog-amplitude values. Cref is connected to the non-inverting input of the 1st amplifier.

Due to the parasitic capacitance generated in the wire connections of Cin pins and their patterns, as well as the one generated between the wire patterns of Cin and Cdrv pins, Cref may not detect capacitance change of each Cin pin accurately. In this case, connect an appropriate capacitance between Cref and Cdrv to detect capacitance change accurately.

However, if the difference between the parasitic capacitance of each Cin pin is extremely large, it may not detect capacitance change of each Cin pin correctly.

CrefAdd can be used as additional terminal for Cref. Leave the CrefAdd open if not in used.

#### Cdrv

It is the output pin for capacitance sensors drive. It outputs the pulse voltage which is needed to detect capacitance at Cin0 to Cin15.

Cdrv and Cin wire patterns should be close to each other so that they are capacitively coupled.

#### INTOUT

It is the interrupt-output pin.

It is used by connecting to a main microcomputer if necessary, and use as interrupt signal. (High Active) Leave the terminal open if not in used.

#### •SCL/SCK

Clock input (I<sup>2</sup>C) / Clock input (SPI)

It is the clock input pin of the I<sup>2</sup>C compatible bus or the SPI depending on the mode of operation.

<sup>\*2)</sup> When VSS terminal is not grounded in battery-powered mobile equipment, detection sensitivity may be degraded.

#### nCS

Interface selection / Chip-select-inverting input (SPI)

Selection of  $I^2C$  compatible bus mode or SPI mode is through this terminal. After initialization, the LSI is automatically in  $I^2C$  compatible bus mode. To continually use  $I^2C$  compatible bus mode, fix nCS pin to "High". To switch to SPI mode after LSI initialization, change the nCS input "High"  $\rightarrow$  "Low". The nCS pin is used as the chipselect-inverting input pin of SPI, and SPI mode is kept until LSI is again initialized.

#### nRST

It is the external-reset-signal-inverting-input pin. When nRST pin is "Low", LSI is in reset state. Each pin (Cin0 to 15, Cref, CrefAdd) is "Hi-Z" during reset state.

#### •SDA/SI

Data input and output (I<sup>2</sup>C) / Data input (SPI)

It is the data input and output pin of the I<sup>2</sup>C compatible bus or the data input pin of the SPI depending on the mode of operation.

#### •SA0/SO

Slave address selection (I<sup>2</sup>C) / Data output (SPI)

It is the slave address selection pin of the I<sup>2</sup>C compatible bus or the data output pin of the SPI depending on the mode of operation.

#### •SA1

Slave address selection (I<sup>2</sup>C)

It is the slave address selection pin of the I<sup>2</sup>C compatible bus.

When SPI mode, connect to the SA1 pin to GND.

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